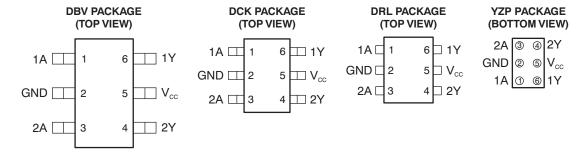


#### **FEATURES**

- Available in the Texas Instruments
   NanoFree™ Package
- Optimized for 1.8-V Operation and Is 3.6-V I/O Tolerant to Support Mixed-Mode Signal Operation
- I<sub>off</sub> Supports Partial-Power-Down Mode Operation
- Sub-1-V Operable
- Max t<sub>pd</sub> of 1.6 ns at 1.8 V

- Low Power Consumption, 10 μA at 1.8 V
- ±8-mA Output Drive at 1.8 V
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)



### **DESCRIPTION/ORDERING INFORMATION**

This dual buffer gate is operational at 0.8-V to 2.7-V  $V_{CC}$ , but is designed specifically for 1.65-V to 1.95-V  $V_{CC}$  operation.

The SN74AUC2G34 performs the Boolean function Y = A in positive logic.

NanoFree™ package technology is a major breakthrough in IC packaging concepts, using the die as the package.

This device is fully specified for partial-power-down applications using  $I_{off}$ . The  $I_{off}$  circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

### ORDERING INFORMATION

T <sub>A</sub>	PACKAGE <sup>(1)</sup>		ORDERABLE PART NUMBER	TOP-SIDE MARKING(2)
	NanoFree <sup>™</sup> – WCSP (DSBGA) 0.23-mm Large Bump – YZP (Pb-free)	Reel of 3000	SN74AUC2G34YZPR	U9_
-40°C to 85°C	SOT-563 – DRL	Reel of 4000	SN74AUC2G34DRLR	U9_
	SOT-23 – DBV	Reel of 3000	SN74AUC2G34DBVR	U34_
	SC-70 - DCK	Reel of 3000	SN74AUC2G34DCKR	U9_

<sup>(1)</sup> Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

NanoFree is a trademark of Texas Instruments.

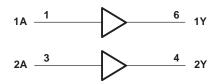
<sup>(2)</sup> DBV/DCK/DRL: The actual top-side marking has one additional character that designates the assembly/test site. YZP: The actual top-side marking has three preceding characters to denote year, month, and sequence code, and one following character to designate the assembly/test site. Pin 1 identifier indicates solder-bump composition (1 = SnPb, • = Pb-free).



# FUNCTION TABLE (EACH GATE)

INPUT A	OUTPUT Y
Н	Н
L	L

### **LOGIC DIAGRAM (POSITIVE LOGIC)**



### **Absolute Maximum Ratings**(1)

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
$V_{CC}$	Supply voltage range		-0.5	3.6	V
VI	Input voltage range <sup>(2)</sup>		-0.5	4.1	V
Vo	Voltage range applied to any output in the I	high-impedance or power-off state <sup>(2)</sup>	-0.5	4.1	V
Vo	Output voltage range <sup>(2)</sup>		-0.5	$V_{CC} + 0.5$	V
I <sub>IK</sub>	Input clamp current	V <sub>I</sub> < 0		-50	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		-50	mA
Io	Continuous output current			±20	mA
	Continuous current through $V_{CC}$ or GND			±100	mA
		DBV package		165	
0	Decks as the small impedance (3)	DCK package		259	°C/W
$\theta_{JA}$	Package thermal impedance <sup>(3)</sup>	DRL package		142	C/VV
		YZP package		123	
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

<sup>(2)</sup> The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>(3)</sup> The package thermal impedance is calculated in accordance with JESD 51-7.



# Recommended Operating Conditions<sup>(1)</sup>

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		0.8	2.7	V
		V <sub>CC</sub> = 0.8 V	V <sub>CC</sub>		
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 1.1 V to 1.95 V	0.65 × V <sub>CC</sub>		V
		$V_{CC}$ = 2.3 V to 2.7 V	1.7		
		V <sub>CC</sub> = 0.8 V		0	
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 1.1 V to 1.95 V	(	).35 × V <sub>CC</sub>	V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	
VI	Input voltage		0	3.6	V
Vo	Output voltage		0	V <sub>CC</sub>	V
		V <sub>CC</sub> = 0.8 V		-0.7	
		V <sub>CC</sub> = 1.1 V		-3	
I <sub>OH</sub>	High-level output current	V <sub>CC</sub> = 1.4 V		-5	mA
		V <sub>CC</sub> = 1.65 V		-8	
		V <sub>CC</sub> = 2.3 V		-9	
		V <sub>CC</sub> = 0.8 V		0.7	
		V <sub>CC</sub> = 1.1 V		3	
I <sub>OL</sub>	Low-level output current	V <sub>CC</sub> = 1.4 V		5	mA
		V <sub>CC</sub> = 1.65 V		8	
		V <sub>CC</sub> = 2.3 V		9	
		$V_{CC} = 0.8 \text{ V to } 1.65 \text{ V}^{(2)}$		20	
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}^{(3)}$		20	ns/V
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}^{(3)}$			
T <sub>A</sub>	Operating free-air temperature		-40	85	°C

All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.
 The data was taken at C<sub>L</sub> = 15 pF, R<sub>L</sub> = 2 kΩ (see Figure 1).
 The data was taken at C<sub>L</sub> = 30 pF, R<sub>L</sub> = 500 Ω (see Figure 1).



### **Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V <sub>cc</sub>	MIN TYP(1)	MAX	UNIT
	$I_{OH} = -100 \mu A$	0.8 V to 2.7 V	V <sub>CC</sub> – 0.1		
	$I_{OH} = -0.7 \text{ mA}$	0.8 V	0.55		
V	$I_{OH} = -3 \text{ mA}$	1.1 V	0.8		V
V <sub>OH</sub>	$I_{OH} = -5 \text{ mA}$	1.4 V	1		V
	$I_{OH} = -8 \text{ mA}$	1.65 V	1.2		
	$I_{OH} = -9 \text{ mA}$	2.3 V	1.8		
	I <sub>OL</sub> = 100 μA	0.8 V to 2.7 V		0.2	
	$I_{OL} = 0.7 \text{ mA}$	0.8 V	0.25		
V	I <sub>OL</sub> = 3 mA	1.1 V		0.3	V
V <sub>OL</sub>	I <sub>OL</sub> = 5 mA	1.4 V		0.4	V
	I <sub>OL</sub> = 8 mA	1.65 V		0.45	
	I <sub>OL</sub> = 9 mA	2.3 V		0.6	
I <sub>I</sub> A inputs	$V_I = V_{CC}$ or GND	0 to 2.7 V		±5	μΑ
I <sub>off</sub>	$V_I$ or $V_O = 2.7 V$	0		±10	μΑ
I <sub>CC</sub>	$V_I = V_{CC}$ or GND, $I_O = 0$	0.8 V to 2.7 V		10	μΑ
C <sub>i</sub>	$V_I = V_{CC}$ or GND	2.5 V	2		pF

<sup>(1)</sup> All typical values are at  $T_A = 25$ °C.

### **Switching Characteristics**

over recommended operating free-air temperature range,  $C_L = 15 \text{ pF}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 0.8 V	V <sub>CC</sub> = ± 0.	1.2 V 1 V	V <sub>CC</sub> = ± 0.			<sub>C</sub> = 1.8 0.15 V		V <sub>CC</sub> = ± 0.		UNIT
	(INFOT)	(001701)	TYP	MIN	MAX	MIN	MAX	MIN	TYP	MAX	MIN	MAX	
t <sub>pd</sub>	А	Y	6.4	0.7	3.4	0.6	2.3	0.6	1	1.6	0.5	1.2	ns

### **Switching Characteristics**

over recommended operating free-air temperature range,  $C_L = 30 \text{ pF}$  (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)		<sub>C</sub> = 1.8 : 0.15 \		V <sub>CC</sub> = ± 0.		UNIT
	(INFOI)	(001701)	MIN	TYP	MAX	MIN	MAX	
t <sub>pd</sub>	A	Υ	0.7	1.3	2.4	0.6	1.8	ns

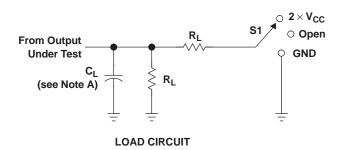
# **Operating Characteristics**

 $T_A = 25^{\circ}C$ 

	PARAMETER	TEST CONDITIONS	V <sub>CC</sub> = 0.8 V TYP	V <sub>CC</sub> = 1.2 V TYP	V <sub>CC</sub> = 1.5 V TYP	V <sub>CC</sub> = 1.8 V TYP	V <sub>CC</sub> = 2.5 V TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	f = 10 MHz	12	12	12	13	14	pF

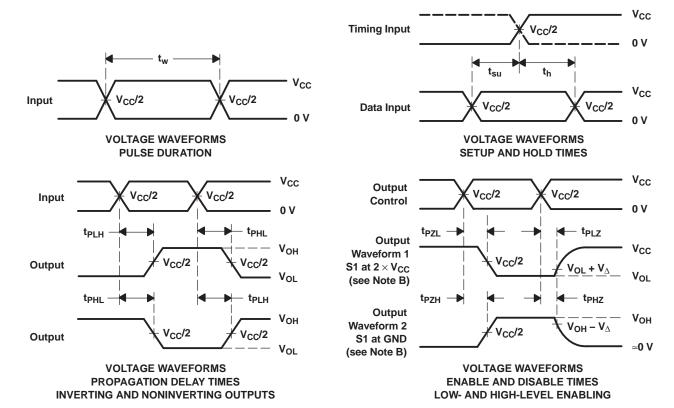


### PARAMETER MEASUREMENT INFORMATION



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	$2 \times V_{CC}$
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

V <sub>CC</sub>	CL	R <sub>L</sub>	$V_{\Delta}$
0.8 V	15 pF	<b>2 k</b> Ω	0.1 V
1.2 V ± 0.1 V	15 pF	<b>2 k</b> Ω	0.1 V
1.5 V ± 0.1 V	15 pF	<b>2 k</b> Ω	0.1 V
1.8 V ± 0.15 V	15 pF	<b>2 k</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	15 pF	<b>2 k</b> Ω	0.15 V
1.8 V ± 0.15 V	30 pF	<b>1 k</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	30 pF	500 Ω	0.15 V



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_0 = 50 \Omega$ , slew rate  $\geq$  1 V/ns.
- D. The outputs are measured one at a time, with one transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F. t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- G. t<sub>PLH</sub> and t<sub>PHL</sub> are the same as t<sub>pd</sub>.
- H. All parameters and waveforms are not applicable to all devices.

Figure 1. Load Circuit and Voltage Waveforms

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### PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74AUC2G34DBVR	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	U34R	Samples
SN74AUC2G34DCKR	ACTIVE	SC70	DCK	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(U95, U9F, U9R)	Samples
SN74AUC2G34DCKRE4	ACTIVE	SC70	DCK	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(U95, U9F, U9R)	Samples
SN74AUC2G34DRLR	ACTIVE	SOT-5X3	DRL	6	4000	RoHS & Green	NIPDAU   NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	(1KB, U97, U9R)	Samples
SN74AUC2G34YZPR	ACTIVE	DSBGA	YZP	6	3000	RoHS & Green	SNAGCU	Level-1-260C-UNLIM	-40 to 85	U9N	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



### PACKAGE OPTION ADDENDUM

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# **PACKAGE MATERIALS INFORMATION**

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### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AUC2G34DBVR	SOT-23	DBV	6	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
SN74AUC2G34DRLR	SOT-5X3	DRL	6	4000	180.0	8.4	2.0	1.8	0.75	4.0	8.0	Q3
SN74AUC2G34YZPR	DSBGA	YZP	6	3000	178.0	9.2	1.02	1.52	0.63	4.0	8.0	Q1

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 5-Oct-2024

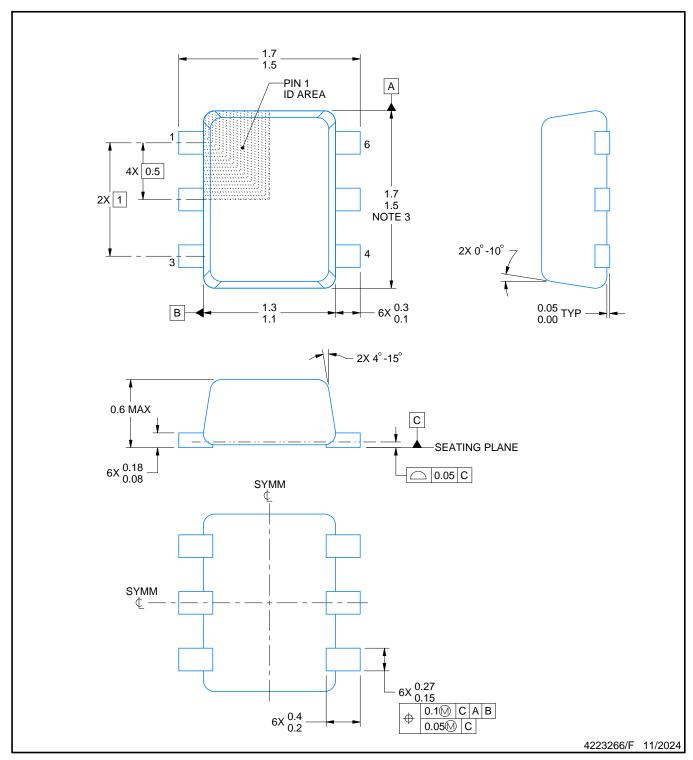


### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AUC2G34DBVR	SOT-23	DBV	6	3000	202.0	201.0	28.0
SN74AUC2G34DRLR	SOT-5X3	DRL	6	4000	210.0	185.0	35.0
SN74AUC2G34YZPR	DSBGA	YZP	6	3000	220.0	220.0	35.0



PLASTIC SMALL OUTLINE



### NOTES:

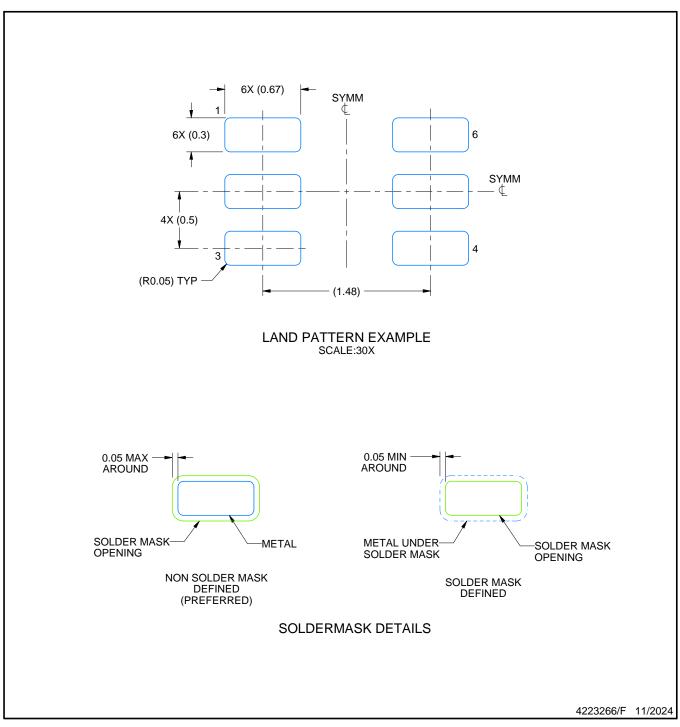
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
  4. Reference JEDEC registration MO-293 Variation UAAD



PLASTIC SMALL OUTLINE

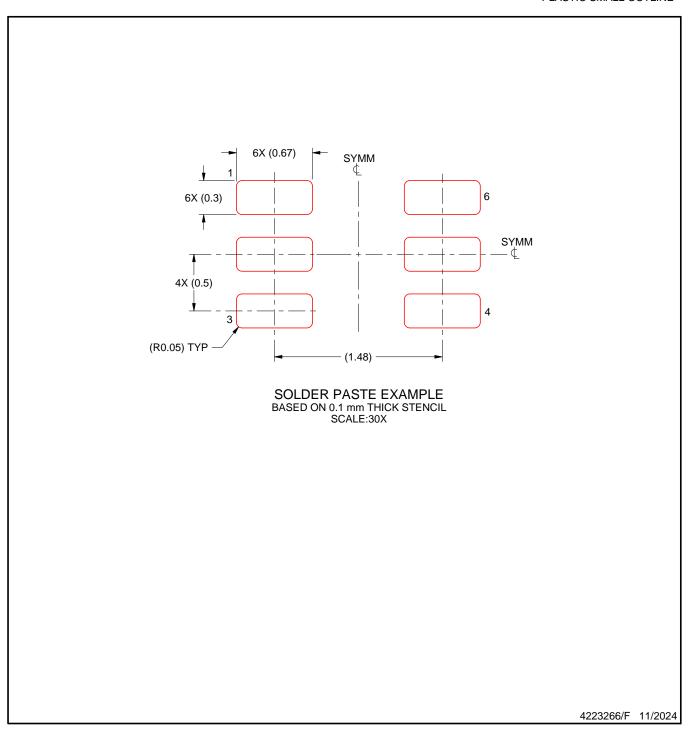


NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.7. Land pattern design aligns to IPC-610, Bottom Termination Component (BTC) solder joint inspection criteria.



PLASTIC SMALL OUTLINE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.

- 4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
- 5. Refernce JEDEC MO-178.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





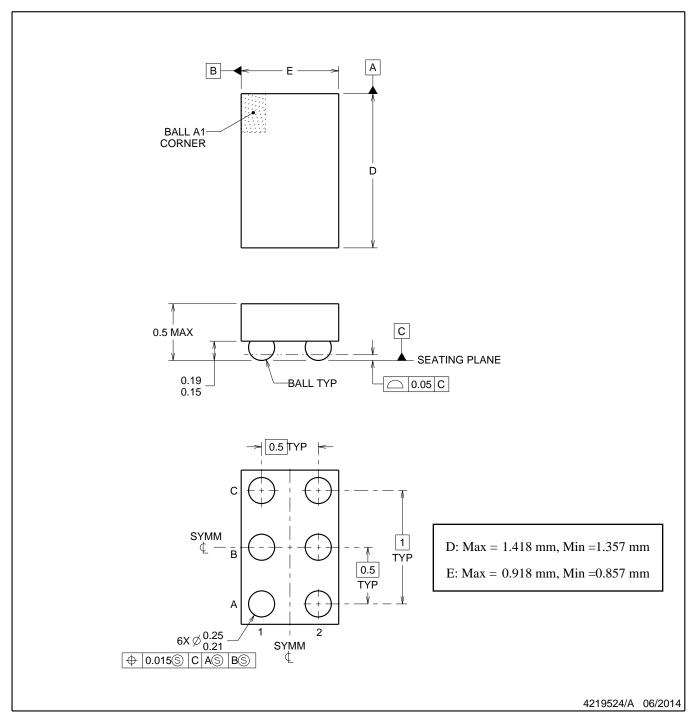
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





DIE SIZE BALL GRID ARRAY



### NOTES:

NanoFree Is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.
- 3. NanoFree<sup>™</sup> package configuration.



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SBVA017 (www.ti.com/lit/sbva017).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.







### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.

  4. Falls within JEDEC MO-203 variation AB.





NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



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